



Gallium Nitride 50V, 1000W, 2.5-2.7GHz RF Power Transistor

Description

The STCV271K0CY4V is a 1000-watt, internally matched GaN HEMT, designed for 5G cellular applications with frequencies from 2.5-2.7GHz, **enabled by wide band VBW capability to support IBW up to 200MHz.**

It can be configured as asymmetrical Doherty for 4G or 5G application, delivering 115 to 140W average power, according to normal 9.5 to 8.5dB back off.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical Doherty Pulsed CW and 1C W--CDMA Characterization Performance within **2.5-2.7GHz**:

$V_{DD} = 50 \text{ Vdc}$, $I_{DQA} = 260 \text{ mA}$, $V_{GSB} = -5.3 \text{ Vdc}$,

1C WCDMA; Signal PAR = 10 dB @ 0.01% Probability on CCDF.

Freq (GHz)	Pulse CW Signal ⁽¹⁾				$P_{avg}=50.5\text{dBm}$ WCDMA Signal ⁽²⁾		
	P3 (dBm)	P3 (W)	P4 (dBm)	P4 (W)	Gp (dB)	η_D (%)	ACPR _{5M} (dBc)
2.50	59.52	897	60.36	1085	13.63	51.35	-30.40
2.60	60.12	1028	60.45	1109	13.37	51.39	-31.29
2.70	59.90	976	60.05	1011	12.80	51.98	-29.09

- Typical Doherty Pulsed CW and 1C W--CDMA Characterization Performance within **2.62-2.69GHz**:

$V_{DD} = 50 \text{ Vdc}$, $I_{DQA} = 260 \text{ mA}$, $V_{GSB} = -5.3 \text{ Vdc}$,

1C WCDMA; Signal PAR = 10 dB @ 0.01% Probability on CCDF.

Freq (GHz)	Pulse CW Signal ⁽¹⁾				$P_{avg}=50.5\text{dBm}$ WCDMA Signal ⁽²⁾		
	P3 (dBm)	P3 (W)	P4 (dBm)	P4 (W)	Gp (dB)	η_D (%)	ACPR _{5M} (dBc)
2.62	51.35	136	60.15	1035	13.03	52.30	-31.31
2.655	50.85	121	60.08	1018	12.80	52.61	-29.83
2.69	50.80	120	60.02	1005	12.78	52.50	-28.56

Driver options:

- STAV27130C6 (1 stage Doherty discrete)

Applications

- Asymmetrical Doherty amplifier within N41 5G band and B41 4G band
- S band power amplifier

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

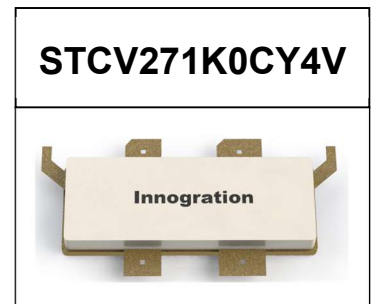




Figure 1: Pin Connection definition

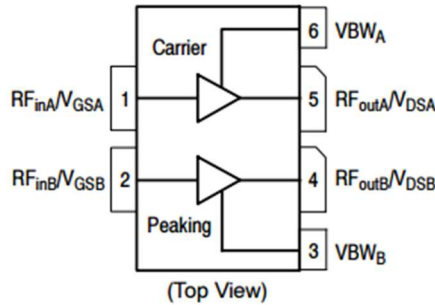


Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain—Source Voltage	V_{DSS}	+200	Vdc
Gate—Source Voltage	V_{GS}	-8 to +0.5	Vdc
Operating Voltage	V_{DD}	55	Vdc
Maximum gate current	I_{gs}	131	mA
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_c	+150	°C
Operating Junction Temperature	T_j	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case by FEA $T_c = 85^\circ\text{C}$, $P_{out} = 120\text{W}$, 2.6GHz Doherty application board	$R_{\theta JC}$	TBD	°C /W

Table 3. Electrical Characteristics (TA = 25°C unless otherwise noted)

DC Characteristics (main path, measured on wafer prior to packaging)

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS} = -8\text{V}$; $I_{DS} = 47\text{mA}$	V_{DSS}		200		V
Gate Threshold Voltage	$V_{DS} = 10\text{V}$, $I_D = 47\text{mA}$	$V_{GS(th)}$	-4		-2	V
Gate Quiescent Voltage	$V_{DS} = 50\text{V}$, $I_{DS} = 240\text{mA}$, Measured in Functional Test	$V_{GS(Q)}$		-3.1		V

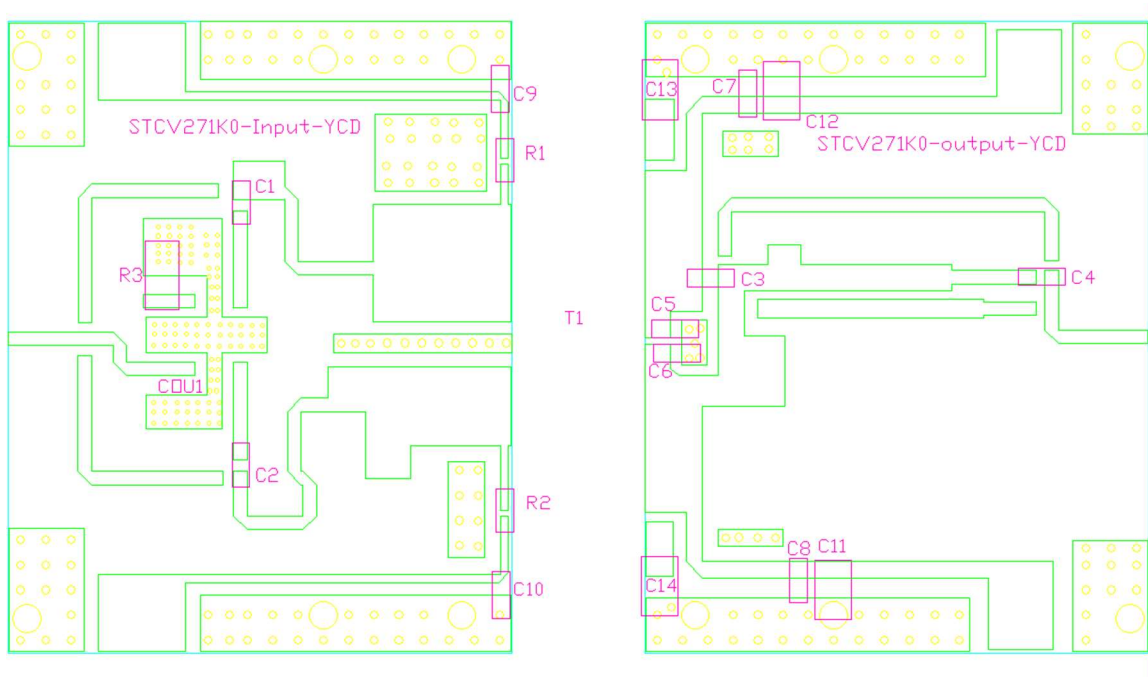
DC Characteristics (peak path, measured on wafer prior to packaging)

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS} = -8\text{V}$; $I_{DS} = 84\text{mA}$	V_{DSS}		200		V
Gate Threshold Voltage	$V_{DS} = 10\text{V}$, $I_D = 84\text{mA}$	$V_{GS(th)}$	-4		-2	V
Gate Quiescent Voltage	$V_{DS} = 50\text{V}$, $I_{DS} = 400\text{mA}$ Measured in Functional Test	$V_{GS(Q)}$		-3.1		V

Ruggedness Characteristics

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Load mismatch capability	2.6GHz, $P_{out} = 120\text{W}$ WCDMA 1 Carrier in Doherty circuit All phase, No device damages	VSWR		10:1		

Figure 3: Picture of application board Doherty circuit for 2.5-2.7GHz



Part	Quantity	Description	Part Number	Manufacture
C1,C2 C4,C7,C8,C9,C10	7	10pF High Q Capacitor	251SHS100BSE	TEMEX
C3	1	3.9pF High Q Capacitor	251SHS3R9BSE	TEMEX
C5	1	1.3pF High Q Capacitor	251SHS1R3BSE	TEMEX
C6	1	1.1pF High Q Capacitor	251SHS1R1BSE	TEMEX
C11,C12,C13,C14	4	10uF MLCC	RS80R2A106M	MARUWA
R1,R2	2	10 Ω Power Resistor	ESR03EZPF100	ROHM
R3	1	51 Ω Power Resistor	RFR50-20CT0421B	YT
COU1	1	3 dB Bridge	X3C26P1-03S	Anaren
T1	1	1000W GaN Dual Transistor	STCV271K0CY4V	Innogrations



Figure 4: Efficiency and power gain as function of Pout

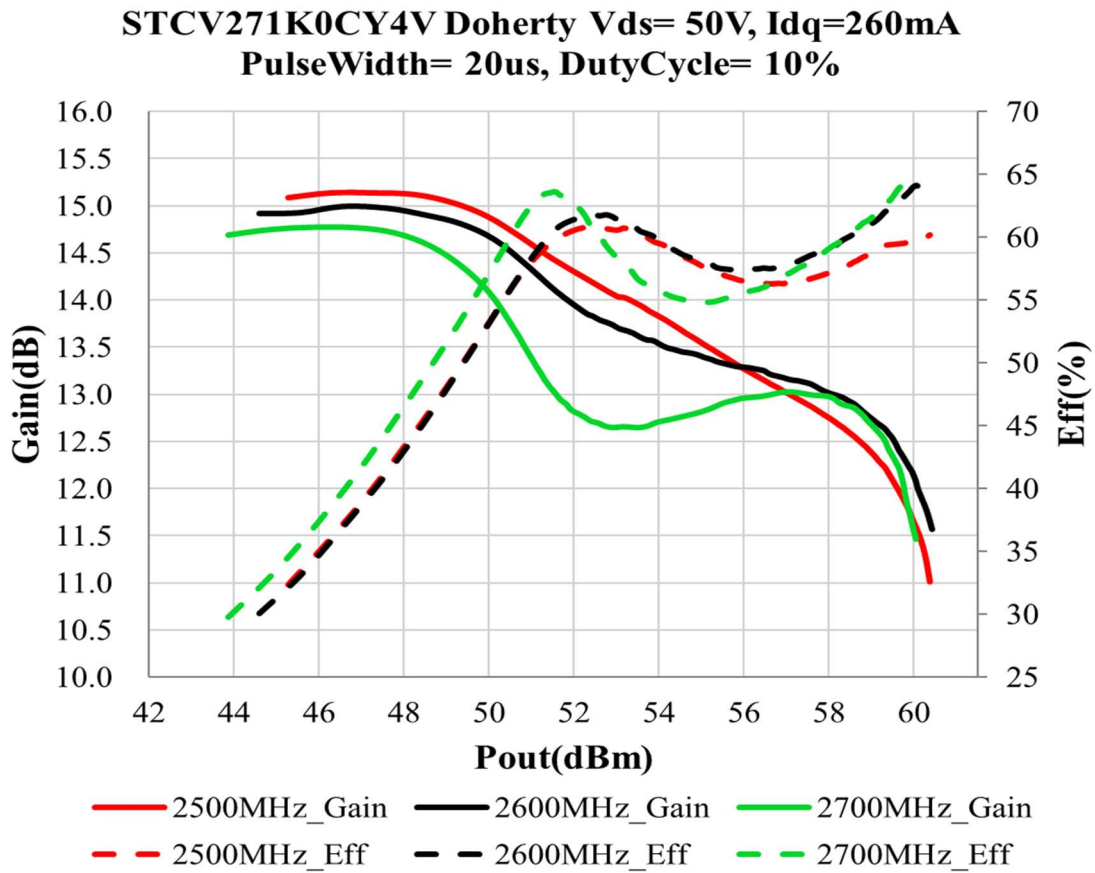
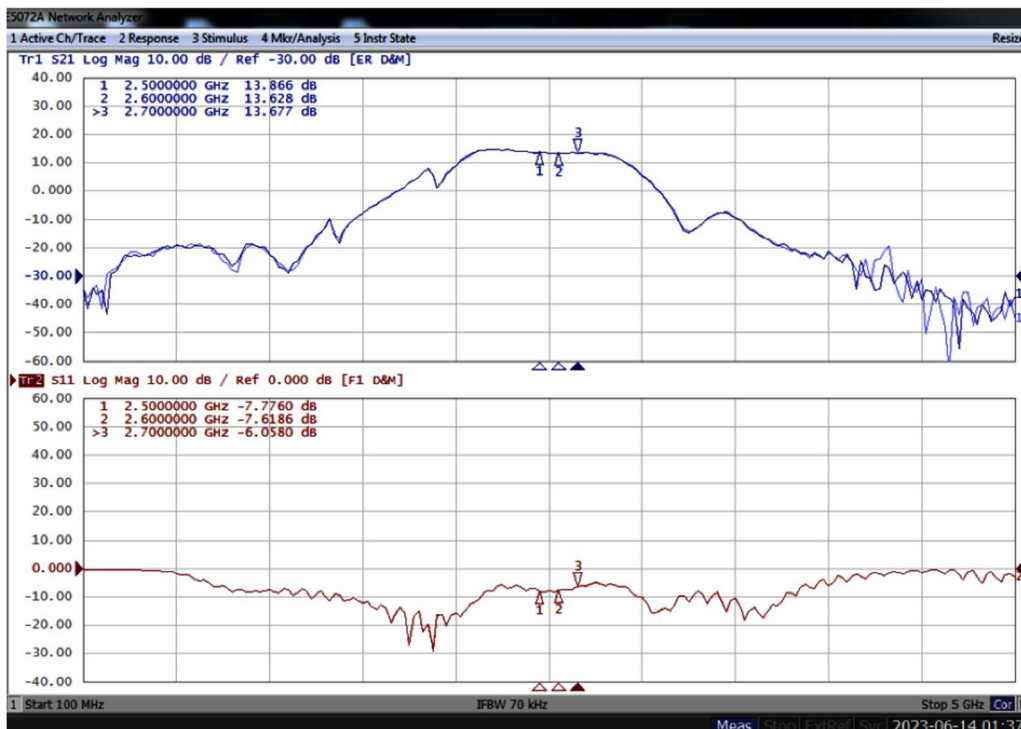
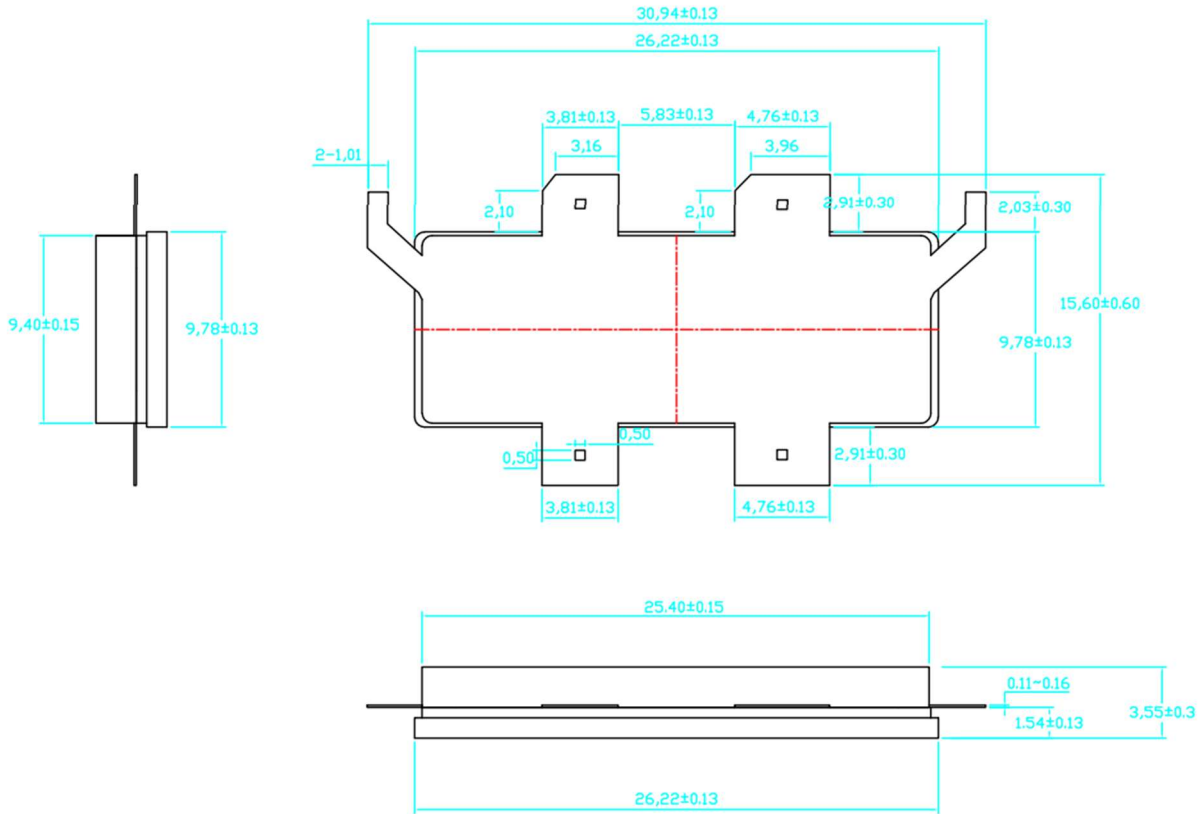


Figure 5: Network analyzer output, S11 and S21





Earless Flanged Ceramic Package; 6 leads- CY4V



Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2023/5/12	V1.0	Objective Datasheet Creation
2023/6/16	V1.0	Preliminary Datasheet Creation

Application data based on LWH-23-14/15

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